



Product data sheet

www.msksemi.com







SOT-23-3L

G

D

Features

- 20V, 6.5A, RDS(ON)=16mΩ@VGS=4.5V
- *Improved dv/dt capability*
- Fast switching
- Green Device Available

Applications

- Notebook
- Load Switch
- Hend-Held Instruments

BVDSS	RDSON	ID
20V	16mΩ	6.5A

Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	20	V
V _{GS}	Gate-Source Voltage	±12	V
1	Drain Current – Continuous (T _C =250)	6.5	A
ID	Drain Current – Continuous (T _C =1000)	4.2	A
I _{DM}	Drain Current – Pulsed ¹	26.8	A
D	Power Dissipation (T _c =250)	1.56	W
PD	Power Dissipation – Derate above 250	0.012	W/ C
Tstg	Storage Temperature Range	-55 to 150	C
TJ	Operating Junction Temperature Range	-55 to 150	С

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		80	C/W



Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} =0V , I _D =250uA	20			V
	BV _{DSS} Temperature Coefficient	Reference to 25C , I_D =1mA		0.02		V/ C
	Drain-Source Leakage Current	V _{DS} =20V , V _{GS} =0V , T _J =250			1	uA
IDSS		V _{DS} =16V , V _{GS} =0V , T _J =1250			10	uA
lgss	Gate-Source Leakage Current	$V_{GS}=\pm 10V$, $V_{DS}=0V$			±100	nA

On Characteristics

R _{DS(ON)} Static Drain-Source O	Static Drain-Source On-Resistance	V _{GS} =4.5V , I _D =4A		16	22	mΩ
		V _{GS} =2.5V , I _D =3A		18	24	1152
V _{GS(th)}	Gate Threshold Voltage			0.6	1.0	V
$ riangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient			2		mV/ C
gfs	Forward Transconductance	V _{DS} =10V , I _S =4A		9.5		S

Dynamic and switching Characteristics

Qg	Total Gate Charge ^{2,3}		 5.8	
Q _{gs}	Gate-Source Charge ^{2,3}	V _{DS} =10V , V _{GS} =4.5V , I _D =4A	 0.6	 nC
Q _{gd}	Gate-Drain Charge ^{2,3}		 2	
T _{d(on)}	Turn-On Delay Time ^{2,3}		 5.0	
Tr	Rise Time ^{2,3}	$V_{\text{DD}}\text{=}10V$, $V_{\text{GS}}\text{=}4.5V$, $R_{\text{G}}\text{=}25\Omega$	 14.4	 nS
T _{d(off)}	Turn-Off Delay Time ^{2,3}	I _D =1A	 30.0	 115
T _f	Fall Time ^{2,3}		 9.2	
Ciss	Input Capacitance		 600	
Coss	Output Capacitance	V_{DS} =10V , V_{GS} =0V , F=1MHz	 70	 pF
Crss	Reverse Transfer Capacitance		 45	

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V _G =V _D =0V , Force Current			6.5	A
Ism	Pulsed Source Current				13	A
Vsd	Diode Forward Voltage	V _{GS} =0V , I _S =1A , T _J =250			1.2	V

Note :

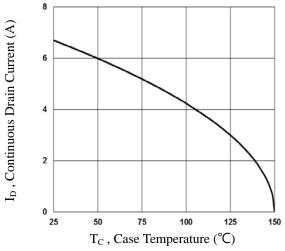
1. Repetitive Rating : Pulsed width limited by maximum junction temperature.

2. The data tested by pulsed , pulse width $\ \leq \ 300 \, \text{us}$, duty cycle $\ \leq \ 2\%$.

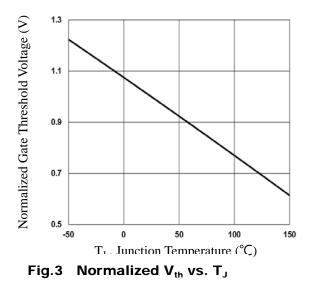
3. Essentially independent of operating temperature.

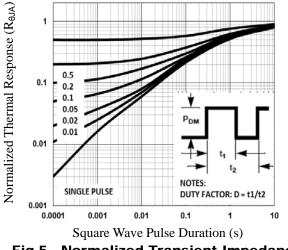














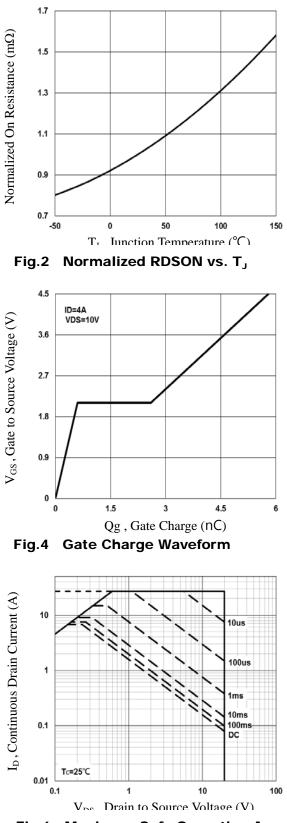


Fig.6 Maximum Safe Operation Area





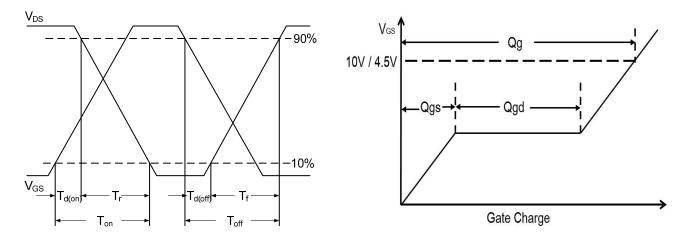


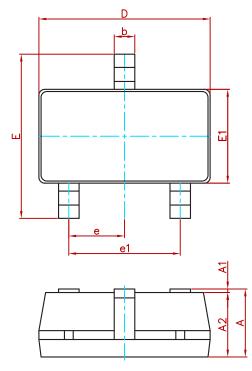
Fig.7 Switching Time Waveform

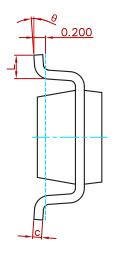
Fig.8 Gate Charge Waveform





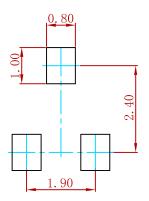
PACKAGE MECHANICAL DATA





Symbol	Dimensions Ir	n Millimeters	Dimension	s In Inches
Symbol	Min.	Max.	Min.	Max.
A	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
С	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
е	0.950(BSC)	0.037((BSC)
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°

Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters.

2.General tolerance:± 0.05mm.
3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
AO3416	SOT-23-3L	3000





<u>Attention</u>

■ Any and all MSKSEMI Semiconductor products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your MSKSEMI Semiconductor representative nearest you before using any MSKSEMI Semiconductor products described or contained herein in such applications.

■ MSKSEMI Semiconductor assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications f any and all MSKSEMI Semiconductor products described orcontained herein.

■ Specifications of any and all MSKSEMI Semiconductor products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.

■ MSKSEMI Semiconductor. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with someprobability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits anderror prevention circuits for safedesign, redundant design, and structural design.

■ In the event that any or all MSKSEMI Semiconductor products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from theauthorities concerned in accordance with the above law.

■ No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of MSKSEMI Semiconductor.

■ Information (including circuit diagrams and circuit parameters) herein is for example only ; it is not guaranteed for volume production. MSKSEMI Semiconductor believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.

Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. Whendesigning equipment, referto the "Delivery Specification" for the MSKSEMI Semiconductor productthat you intend to use.